

Notice of References Cited	Application/Control No. 10/807,245	Applicant(s)/Patent Under Reexamination ONO ET AL.	
	Examiner Kenneth A. Parker	Art Unit 2871	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0044437	04-2002	Lee, Joung Jae	362/31
	B	US-2005/0195619	09-2005	Tseng, Wen-Pao	362/561
	C	US-2003/0202363	10-2003	Adachi et al.	362/558
	D	US-6,709,122	03-2004	Adachi et al.	362/27
	E	US-6,923,554	08-2005	Kuo, Heng Sheng	362/223
	F	US-5,384,658	01-1995	Ohtake et al.	359/707
	G	US-6,619,815	09-2003	Southern, Jr., John A.	362/225
	H	US-4,599,684	07-1986	Lee, Richard H.	362/346
	I	US-5,274,533	12-1993	Neary et al.	362/225
	J	US-5,729,311	03-1998	Broer et al.	349/65
	K	US-6,210,019	04-2001	Weathers, Robert W.	362/220
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 09282921 A	10-1997	Japan	KANDA et al.	F21V 08/00
	O	JP 2003257233 A	09-2003	Japan	KIDA et al.	F21V 23/00
	P	JP 09282921 A	10-1997	Japan	KANDA et al.	F21V 08/00
	Q	JP 2002184231 A	06-2002	Japan	HAYASHI et al.	F21V 08/00
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.